US009411007B2

(12) **United States Patent**
Bertacco et al.

(10) **Patent No.: US 9,411,007 B2**
(45) **Date of Patent: Aug. 9, 2016**

(54) **SYSTEM AND METHOD FOR STATISTICAL POST-SILICON VALIDATION**

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(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 505 days.

(21) Appl. No.: **13/663,258**

(22) Filed: **Oct. 29, 2012**

(65) **Prior Publication Data**

US 2015/0268293 A1 Sep. 24, 2015

(51) **Int. Cl.**

G01R 31/26	(2014.01)
G01R 29/26	(2006.01)
G01R 27/28	(2006.01)
G06F 11/263	(2006.01)
G01R 31/3183	(2006.01)
G06F 11/26	(2006.01)
G01R 31/3185	(2006.01)

(52) **U.S. Cl.**

CPC ***G01R 31/2601*** (2013.01); ***G01R 27/28*** (2013.01); ***G01R 29/26*** (2013.01); *G01R 31/3183* (2013.01); *G01R 31/318544* (2013.01); *G06F 11/261* (2013.01); *G06F 11/263* (2013.01)

(58) **Field of Classification Search**

None

See application file for complete search history.

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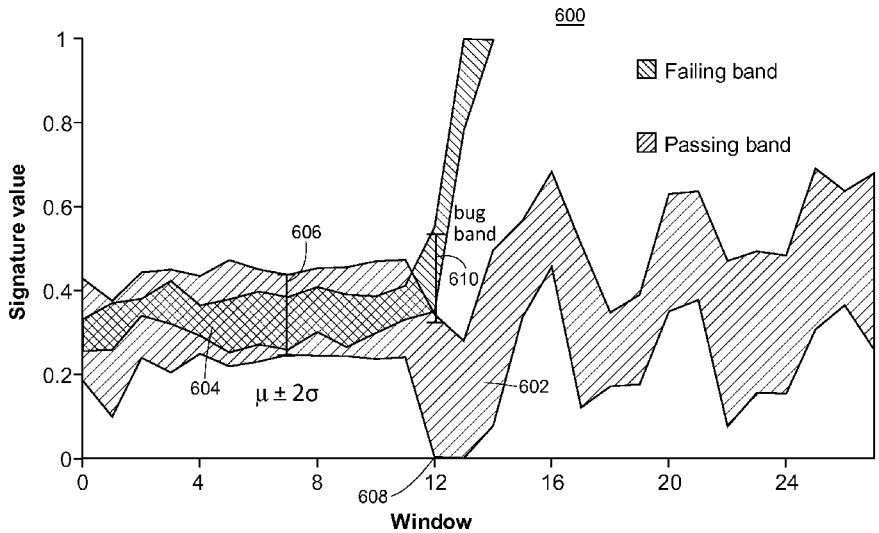
(57) **ABSTRACT**

The system and method described herein relate to a bug positioning system for post-silicon validation of a prototype integrated circuit using statistical analysis. Specifically, the bug positioning system samples output and intermediate signals from a prototype chip to generate signatures. Signatures are grouped into passing and failing groups, modeled, and compared to identify patterns of acceptable behavior and unacceptable behavior and locate bugs in space and time.

20 Claims, 7 Drawing Sheets